

SANYO Semiconductors DATA SHEET

N-Channel Silicon MOSFET

ECH8622R — General-Purpose Switching Device **Applications**

Features

- · Low ON-resistance.
- · Best suited for lithium battery applications.
- 2.5V drive.
- · Composite type, facilitating high-density mounting.
- · Drain common specifications.

Specifications

Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Drain-to-Source Voltage	VDSS		30	V
Gate-to-Source Voltage	VGSS		±12	V
Drain Current (DC)	ID		7	Α
Drain Current (Pulse)	IDP	PW≤10μs, duty cycle≤1%	40	Α
Allowable Power Dissipation	PD	Mounted on a ceramic board (900mm ² X 0.8mm) 1unit	1.4	W
Total Dissipation	PT	Mounted on a ceramic board (900mm ² X 0.8mm)	1.5	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C

Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Offic
Drain-to-Source Breakdown Voltage	V(BR)DSS	ID=1mA, VGS=0V	30			V
Zero-Gate Voltage Drain Current	IDSS	V _{DS} =30V, V _{GS} =0V			1	μΑ
Gate-to-Source Leakage Current	IGSS	V _{GS} =±8V, V _{DS} =0V			±10	μΑ
Cutoff Voltage	VGS(off)	VDS=10V, ID=1mA	0.5		1.3	V
Forward Transfer Admittance	yfs	V _{DS} =10V, I _D =3.5A	6	10		S
Static Drain-to-Source On-State Resistance	R _{DS} (on)1	I _D =4A, V _{GS} =4.5V	12.6	18	23	mΩ
	RDS(on)2	ID=4A, VGS=4.0V	13.3	19	25	$m\Omega$
	RDS(on)3	I _D =4A, V _G S=3.1V	14.3	22	29	mΩ
	R _{DS} (on)4	I _D =2A, V _{GS} =2.5V	15	25	34	mΩ
Input Capacitance	Ciss	V _{DS} =10V, f=1MHz		1220		pF
Output Capacitance	Coss	V _{DS} =10V, f=1MHz		180		pF
Reverse Transfer Capacitance	Crss	V _{DS} =10V, f=1MHz		140		pF

Marking: WG Continued on next page.

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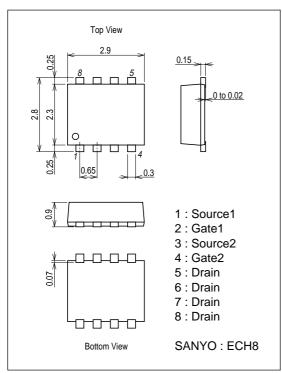
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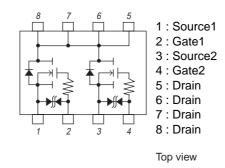
Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	J Gill
Turn-ON Delay Time	t _d (on)	See specified Test Circuit.		585		ns
Rise Time	t _r	See specified Test Circuit.		1680		ns
Turn-OFF Delay Time	td(off)	See specified Test Circuit.		4960		ns
Fall Time	tf	See specified Test Circuit.		2660		ns
Total Gate Charge	Qg	V _{DS} =10V, V _{GS} =4.5V, I _D =7A		14		nC
Gate-to-Source Charge	Qgs	V _{DS} =10V, V _{GS} =4.5V, I _D =7A		2		nC
Gate-to-Drain "Miller" Charge	Qgd	V _{DS} =10V, V _{GS} =4.5V, I _D =7A		4.3		nC
Diode Forward Voltage	V _{SD}	I _S =7A, V _{GS} =0V		0.84	1.2	V

Package Dimensions

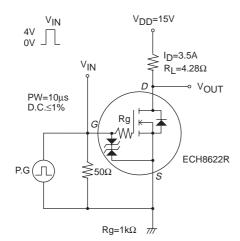
unit : mm 7011A-003

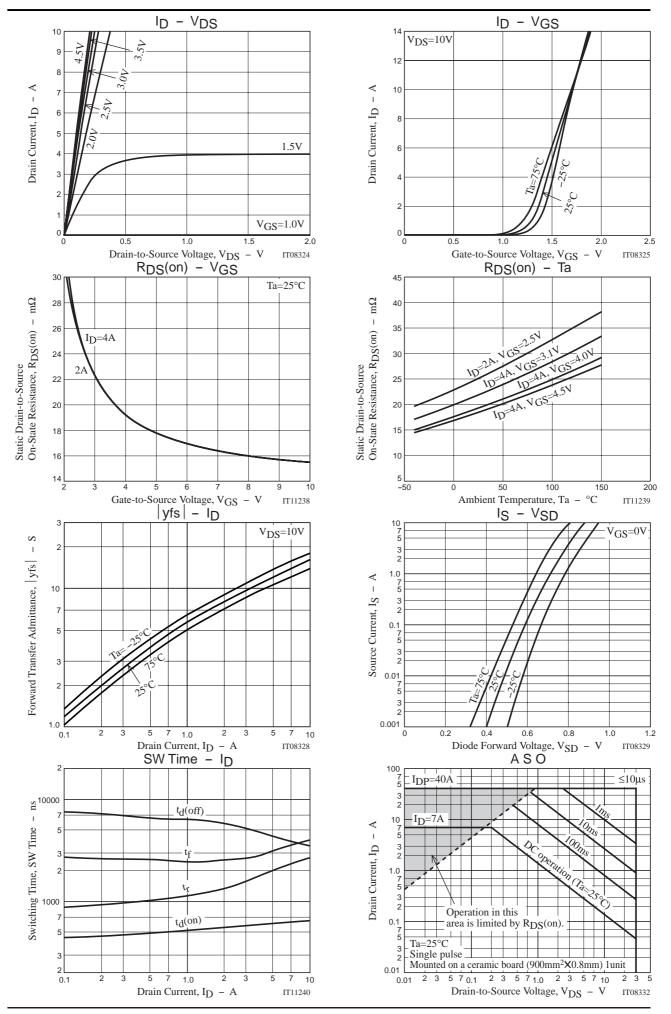


Electrical Connection

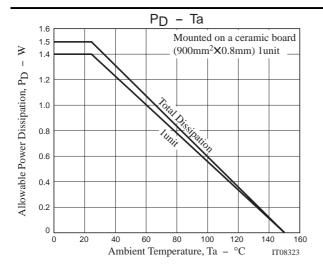


Switching Time Test Circuit





ECH8622R



Note on usage: Since the ECH8622R is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

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